

Form PTO-1449		Docket Number 544952000100		Application Number 10/616,482			
INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>		Applicant Behzad IMANI and Mark L. BRONGERSMA					
		Filing Date July 8, 2003		Group Art Unit Not Yet Assigned			
		Mailing Date September 23, 2003					
U.S. PATENT DOCUMENTS							
Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
NS	1.	05/27/1997	5,633,711	Nelson et al.			
NS	2.	11/09/1999	5,982,482	Nelson et al.			
NS	3.	01/18/2000	6,016,202	Fuchs et al.			
NS	4.	06/13/2000	6,075,602	Fuchs et al.			
NS	5.	01/16/2001	6,175,421	Fuchs et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
OTHER DOCUMENTS						<i>(including author, title, Date, Pertinent Pages, Etc.)</i>	
Examiner Initials	Ref. No.	Title					
NS	6.	Banet, M. et al. (Date Not Known). "All-Optical, Non-Contact Metrology for Characterising CMP of Copper Films," <i>Semiconductor Fabtech</i> , Eleventh Edition, six pages.					
NS	7.	Banet, M. et al. (Date Not Known). "The Future of Metrology is Optical, Fast and In Situ," <i>Future Fab International</i> , four pages.					
NS	8.	Banet, M.J. et al. (1998). "High-Precision Film Thickness Determination Using a Laser-Based Ultrasonic Technique," <i>Applied Physics Letters</i> 73(2):169-171.					
NS	9.	Duggal, A.R. et al. (1992). "Real-Time Optical Characterization of Surface Acoustic Modes of Polyimide Thin-Film Coatings," <i>J. Appl. Phys.</i> 72(7):2823-2839.					
NS	10.	Krastev, P. et al. (2003). "Modeling of Surface Acoustic Waves in Thin Film Stacks with an Arbitrary Number of Layers (abstract)," <i>Review of Scientific Instruments</i> 74(1):738					
NS	11.	Maznev, A.A. and Nelson, K.A. (1998). "Optical Heterodyne Detection of Laser-Induced Gratings," <i>Optics Letters</i> 23(16):1319-1321.					
	12.	Philips (Date Not Known). "Accurate Non-Contact Measurement of Post-CMP Dishing and Erosion in Damascene Structures," <i>Philips Analytical Brochure</i>, four pages.					
	13.	Philips (Date Not Known). "All-Optical Metrology Rapidly Characterizes Copper Damascene Array Structures with Lines Widths Down to 0.07 Micron," <i>Philips Analytical Brochure</i>, two pages.					
EXAMINER:		Michael Stuhl		DATE CONSIDERED:		4-14-05	
EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.							

Note
→ citation not considered because they do not produce
a date of publication.

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**INFORMATION DISCLOSURE CITATION
ON AN APPLICATION**

Applicant

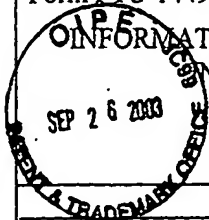
Behzad IMANI and Mark L. BRONGERSMA

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Group Art Unit Not Yet Assigned

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14.	Philips (Date Not Known). "Application Note: Measuring Opaque Films Near the Wafer's Edge," Philips Analytical Brochure, two pages.
15.	Philips (Date Not Known). "Comparing Metrologies for Copper Metallization: Optoacoustics Versus Four Point Probe," Philips Analytical Brochure, two pages.
16.	Reader, A. (2000). "Roadmap Driven Metrology," <i>Metrology</i> , two pages.
17.	Rogers, J.A. et al. (1997). "Optical System for Rapid Materials Characterization with the Transient Grating Technique: Application to Nondestructive Evaluation of Thin Films Used in Microelectronics," <i>Appl. Phys. Lett.</i> 71(2):225-227.

EXAMINER:

Michael Steh

DATE CONSIDERED:

4-14-05

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* Note

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